

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	7043315	wafer\$1 or semiconductor\$1 oe substrate\$1 or chip\$1 or IC or integrated adj circuit or PCB or printed adj circuit adj board	USPAT; US - PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:16
2	BRS	L2	905	(wafer\$1 or semiconductor\$1 or substrate\$1 or chip\$1 or IC or integrated adj circuit or PCB or printed adj circuit adj board) with (repetit\$3 or repepeat\$3) with pattern\$1	USPAT; US - PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:18
3	BRS	L3	720	2 and @ad<20011024	USPAT; US - PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:20
4	BRS	L4	381	3 and (optical or EB or electronic adj beam or e-beam or SEM or scanning adj electronic adj microscopes or UVM or ultra adj violet adj microscopes or SFM or SXM or AFM)	USPAT; US - PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:26
5	BRS	L5	279	4 and (mask\$ or unmask\$3)	USPAT; US - PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:27

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	Type	L #	Hits	Search Text	DBs	Time Stamp
6	BRS	L6	0	5 and cell adj metrics	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:28
7	BRS	L7	2	5 and (contrast near3 data or grey near2 scale)with(cell or array or sliding adj window or metrics)	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:38
8	BRS	L8	165	5 and (cell or array or sliding adj window or metrics)	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 11:22
9	BRS	L9	0	8 and (detect\$3 or determine or fault or flaw or defect)with(edge\$1 or contrast)with(repetit\$3 or repepeat\$3)near3 pattern\$1	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:44
10	BRS	L10	65	8 and (detect\$3 or determine or fault or flaw or defect)with(edge\$1 or contrast)and(repetit\$3 or repepeat\$3)near3 pattern\$1	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 10:45

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	Type	L #	Hits	Search Text	DBs	Time Stamp
11	BRS	L11	33	10 and(shift\$3 or mov\$4)with(cell or array or sliding adj window or metrics)	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 11:24
12	BRS	L12	23	11 and (compar\$5 or match\$3)with(cell or array or slid\$3 adj window or metrics)	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 11:29
13	BRS	L13	8	12 and (reference oo template or test near2 image)with image\$1	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 11:30
14	BRS	L14	8	12 and (reference or template or test near2 image)with image\$1	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/11/08 11:30

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